

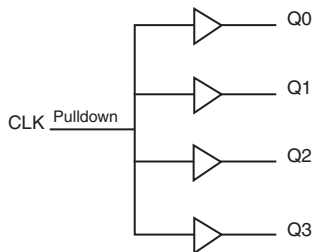
## GENERAL DESCRIPTION

The 8304I is a low skew, 1-to-4 Fanout Buffer. The 8304I is characterized at full 3.3V for input  $V_{DD}$ , and mixed 3.3V and 2.5V for output operating supply modes ( $V_{DDO}$ ). Guaranteed output and part-to-part skew characteristics make the 8304I ideal for those clock distribution applications demanding well defined performance and repeatability.

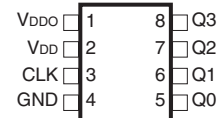
## FEATURES

- Four LVCMOS / LVTTL outputs
- LVCMOS clock input
- CLK can accept the following input levels: LVCMOS, LVTTL
- Maximum output frequency: 166MHz
- Output skew: 60ps (maximum)
- Part-to-part skew: 650ps (maximum)
- Small 8 lead SOIC package saves board space
- 3.3V input, outputs may be either 3.3V or 2.5V supply modes
- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) compliant package

## BLOCK DIAGRAM



## PIN ASSIGNMENT



**8304I**  
**8-Lead SOIC**  
 3.8mm x 4.8mm, x 1.47mm package body  
**M Package**  
 Top View

**TABLE 1. PIN DESCRIPTIONS**

| Number | Name             | Type   |          | Description   |
|--------|------------------|--------|----------|---|
| 1      | V <sub>DDO</sub> | Power  |          | Output supply pin. Connect to 3.3V or 2.5V.             |
| 2      | V <sub>DD</sub>  | Power  |          | Positive supply pin. Connect to 3.3V.                   |
| 3      | CLK              | Input  | Pulldown | LVC MOS / LV TTL clock input.                           |
| 4      | GND              | Power  |          | Power supply ground. Connect to ground.                 |
| 5      | Q0               | Output |          | Single clock output. LVC MOS / LV TTL interface levels. |
| 6      | Q1               | Output |          | Single clock output. LVC MOS / LV TTL interface levels. |
| 7      | Q2               | Output |          | Single clock output. LVC MOS / LV TTL interface levels. |
| 8      | Q3               | Output |          | Single clock output. LVC MOS / LV TTL interface levels. |

NOTE: *Pulldown* refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

**TABLE 2. PIN CHARACTERISTICS**

| Symbol                | Parameter                                  | Test Conditions                             | Minimum | Typical | Maximum | Units |
|-----------------------|--|---|---------|---------|---------|-------|
| C <sub>IN</sub>       | Input Capacitance                          |   |         |         | 4       | pF    |
| C <sub>PD</sub>       | Power Dissipation Capacitance (per output) | V <sub>DD</sub> , V <sub>DDO</sub> = 3.465V |         |         | 15      | pF    |
| R <sub>PULLDOWN</sub> | Input Pulldown Resistor                    |   |         | 51      |         | kΩ    |
| R <sub>OUT</sub>      | Output Impedance                           |   |         | 7       |         | Ω     |

**ABSOLUTE MAXIMUM RATINGS**

|  |                           |
|--|---------------------------|
| Supply Voltage, $V_{DD}$                 | 4.6V                      |
| Inputs, $V_I$                            | -0.5V to $V_{DD} + 0.5V$  |
| Outputs, $V_O$                           | -0.5V to $V_{DDO} + 0.5V$ |
| Package Thermal Impedance, $\theta_{JA}$ | 112.7°C/W (0 lfpm)        |
| Storage Temperature, $T_{STG}$           | -65°C to 150°C            |

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

**TABLE 3A. POWER SUPPLY DC CHARACTERISTICS,  $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ C$  TO  $85^\circ C$** 

| Symbol    | Parameter                   | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------------|-----------------|---------|---------|---------|-------|
| $V_{DD}$  | Power Supply Voltage        |                 | 3.135   | 3.3     | 3.465   | V     |
| $V_{DDO}$ | Output Power Supply Voltage |                 | 3.135   | 3.3     | 3.465   | V     |
| $I_{DD}$  | Power Supply Current        |                 |         |         | 18      | mA    |
| $I_{DDO}$ | Output Supply Current       |                 |         |         | 11      | mA    |

**TABLE 3B. POWER SUPPLY DC CHARACTERISTICS,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDO} = 2.5V \pm 5\%$ ,  $T_A = -40^\circ C$  TO  $85^\circ C$** 

| Symbol    | Parameter               | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-------------------------|-----------------|---------|---------|---------|-------|
| $V_{DD}$  | Positive Supply Voltage |                 | 3.135   | 3.3     | 3.465   | V     |
| $V_{DDO}$ | Output Supply Voltage   |                 | 2.375   | 2.5     | 2.625   | V     |
| $I_{DD}$  | Power Supply Current    |                 |         |         | 18      | mA    |
| $I_{DDO}$ | Output Supply Current   |                 |         |         | 11      | mA    |

**TABLE 3C. LVCMOS / LVTTTL DC CHARACTERISTICS,  $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ C$  TO  $85^\circ C$** 

| Symbol   | Parameter           | Test Conditions                | Minimum | Typical | Maximum        | Units   |
|----------|---------------------|--------------------------------|---------|---------|----------------|---------|
| $V_{IH}$ | Input High Voltage  |                                | 2       |         | $V_{DD} + 0.3$ | V       |
| $V_{IL}$ | Input Low Voltage   |                                | -0.3    |         | 1.3            | V       |
| $I_{IH}$ | Input High Current  | $V_{DD} = V_{IN} = 3.465V$     |         |         | 150            | $\mu A$ |
| $I_{IL}$ | Input Low Current   | $V_{DD} = 3.465V, V_{IN} = 0V$ | -5      |         |                | $\mu A$ |
| $V_{OH}$ | Output High Voltage | Refer to NOTE 1                | 2.6     |         |                | V       |
|          |                     | $I_{OH} = -16mA$               | 2.9     |         |                | V       |
|          |                     | $I_{OH} = -100\mu A$           | 3       |         |                | V       |
| $V_{OL}$ | Output Low Voltage  | Refer to NOTE 1                |         |         | 0.5            | V       |
|          |                     | $I_{OL} = 16mA$                |         |         | 0.25           | V       |
|          |                     | $I_{OL} = 100\mu A$            |         |         | 0.15           | V       |

NOTE 1: Outputs terminated with  $50\Omega$  to  $V_{DDO}/2$ . See Parameter Measurement Section, "3.3V Output Load Test Circuit".

**TABLE 3D. LVCMOS / LVTTTL DC CHARACTERISTICS,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDO} = 2.5V \pm 5\%$ ,  $T_A = -40^\circ C$  TO  $85^\circ C$** 

| Symbol   | Parameter                   | Test Conditions                | Minimum | Typical | Maximum        | Units   |
|----------|-----------------------------|--------------------------------|---------|---------|----------------|---------|
| $V_{IH}$ | Input High Voltage          |                                | 2       |         | $V_{DD} + 0.3$ | V       |
| $V_{IL}$ | Input Low Voltage           |                                | -0.3    |         | 1.3            | V       |
| $I_{IH}$ | Input High Current          | $V_{DD} = V_{IN} = 3.465V$     |         |         | 150            | $\mu A$ |
| $I_{IL}$ | Input Low Current           | $V_{DD} = 3.465V, V_{IN} = 0V$ | -5      |         |                | $\mu A$ |
| $V_{OH}$ | Output High Voltage; NOTE 1 |                                | 2.1     |         |                | V       |
| $V_{OL}$ | Output Low Voltage; NOTE 1  |                                |         |         | 0.5            | V       |

NOTE 1: Outputs terminated with  $50\Omega$  to  $V_{DDO}/2$ . See Parameter Measurement Section, "3.3V/2.5V Output Load Test Circuit".

**TABLE 4A. AC CHARACTERISTICS,  $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ C$  TO  $85^\circ C$** 

| Symbol    | Parameter   | Test Conditions                         | Minimum | Typical | Maximum | Units |
|-----------|---|---|---------|---------|---------|-------|
| $f_{MAX}$ | Output Frequency  |   |         |         | 166     | MHz   |
| $t_{pLH}$ | Propagation Delay, Low-to-High; NOTE 1                                    | $f \leq 166MHz$                         | 2       |         | 3.3     | ns    |
| $t_{jit}$ | Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section | 125MHz, Integration Range 12kHz – 20MHz |         | 0.17    |         | ps    |
| $tsk(o)$  | Output Skew; NOTE 2, 4  | $f = 133MHz$                            |         |         | 50      | ps    |
| $tsk(pp)$ | Part-to-Part Skew; NOTE 3, 4  |   |         |         | 600     | ps    |
| $t_R$     | Output Rise Time  | 30% to 70%                              | 250     |         | 500     | ps    |
| $t_F$     | Output Fall Time  | 30% to 70%                              | 250     |         | 500     | ps    |
| odc       | Output Duty Cycle   |   | 40      |         | 60      | %     |

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE: All parameters measured at 166MHz unless noted otherwise.

NOTE 1: Measured from  $V_{DD}/2$  of the input to  $V_{DDO}/2$  of the output.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at  $V_{DDO}/2$ .

NOTE 3: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of inputs on each device, the outputs are measured

at  $V_{DDO}/2$ .

NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

**TABLE 4B. AC CHARACTERISTICS,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDO} = 2.5V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  TO  $85^\circ\text{C}$** 

| Symbol       | Parameter                              | Test Conditions        | Minimum | Typical | Maximum | Units |
|--------------|--|------------------------|---------|---------|---------|-------|
| $f_{MAX}$    | Output Frequency                       |                        |         |         | 166     | MHz   |
| $t_{p_{LH}}$ | Propagation Delay, Low-to-High; NOTE 1 | $f \leq 166\text{MHz}$ | 2.3     |         | 3.7     | ns    |
| $t_{sk(o)}$  | Output Skew; NOTE 2, 4                 | $f = 133\text{MHz}$    |         |         | 60      | ps    |
| $t_{sk(pp)}$ | Part-to-Part Skew; NOTE 3, 4           |                        |         |         | 650     | ps    |
| $t_R$        | Output Rise Time                       | 30% to 70%             | 250     |         | 500     | ps    |
| $t_F$        | Output Fall Time                       | 30% to 70%             | 250     |         | 500     | ps    |
| odc          | Output Duty Cycle                      |                        | 40      |         | 60      | %     |

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

All parameters measured at 166MHz unless noted otherwise.

NOTE 1: Measured from  $V_{DD}/2$  of the input to  $V_{DDO}/2$  of the output.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at  $V_{DDO}/2$ .

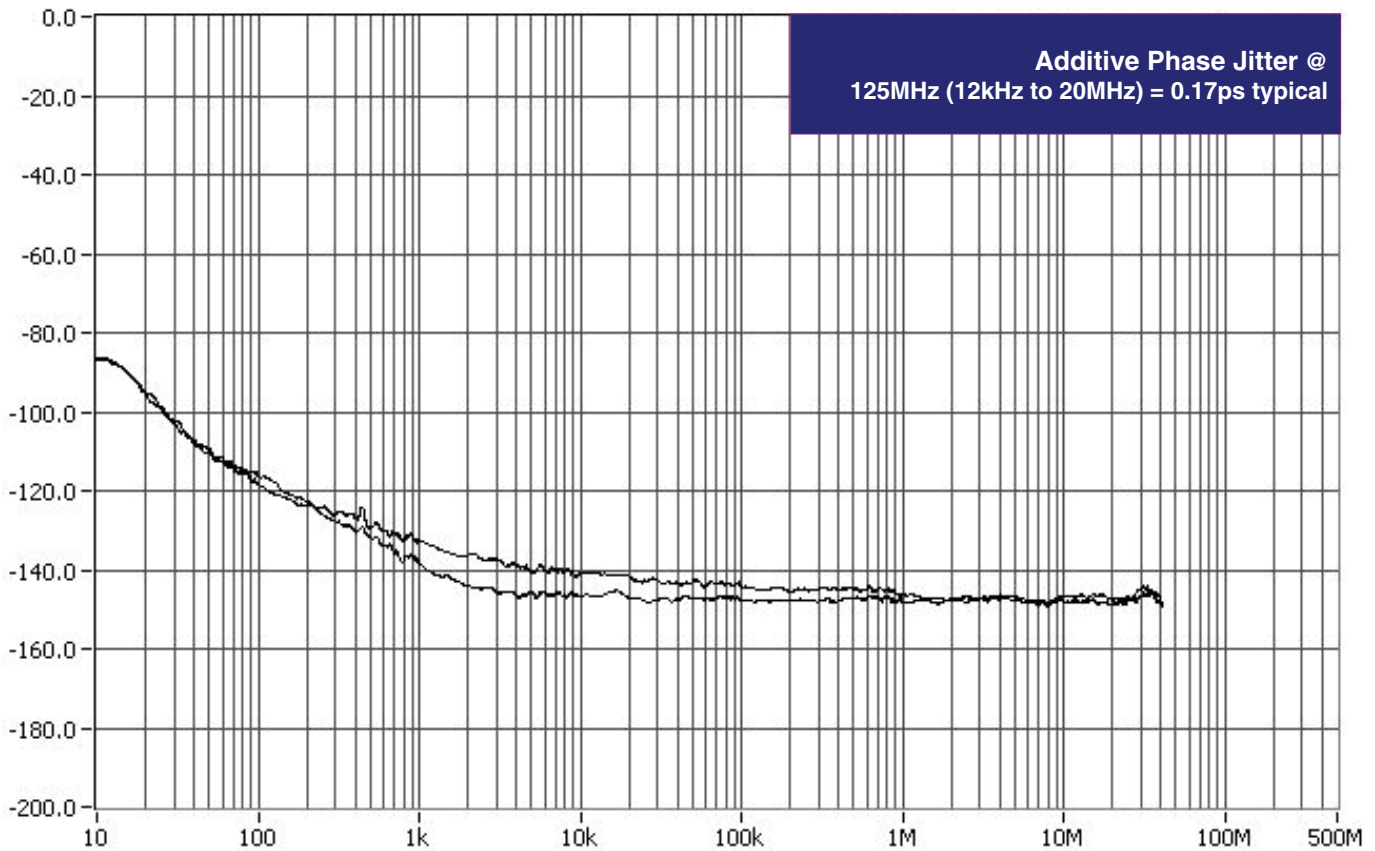
NOTE 3: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at  $V_{DDO}/2$ .

NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

## ADDITIVE PHASE JITTER

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the **dBc Phase Noise**. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels

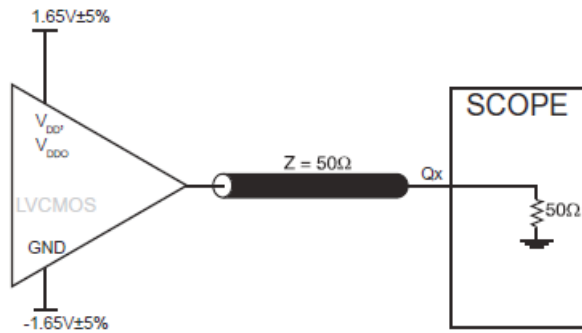
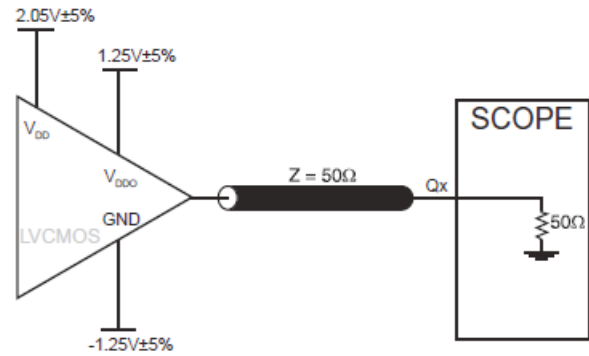
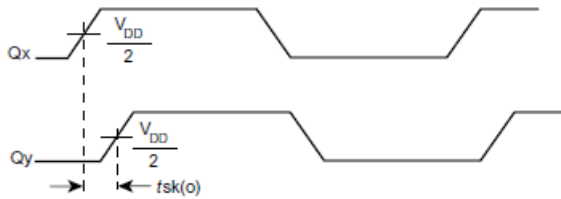
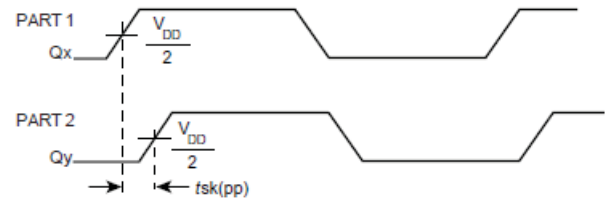
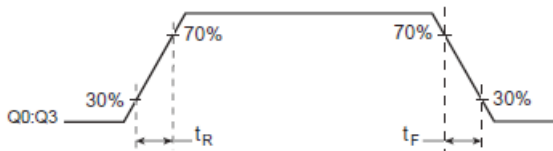
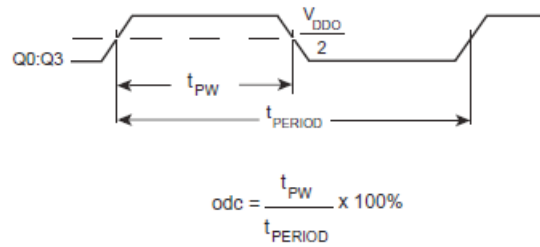
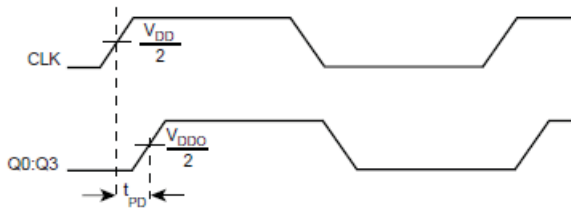
(dBm) or a ratio of the power in the 1Hz band to the power in the fundamental. When the required offset is specified, the phase noise is called a **dBc** value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device.

This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

# PARAMETER MEASUREMENT INFORMATION


**3.3V OUTPUT LOAD AC TEST CIRCUIT**

**2.5V OUTPUT LOAD AC TEST CIRCUIT**

**OUTPUT SKEW**

**PART-TO-PART SKEW**

**OUTPUT RISE/FALL TIME**

**OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD**

**PROPAGATION DELAY**

## RELIABILITY INFORMATION

**TABLE 5.  $\theta_{JA}$  vs. AIR FLOW TABLE**

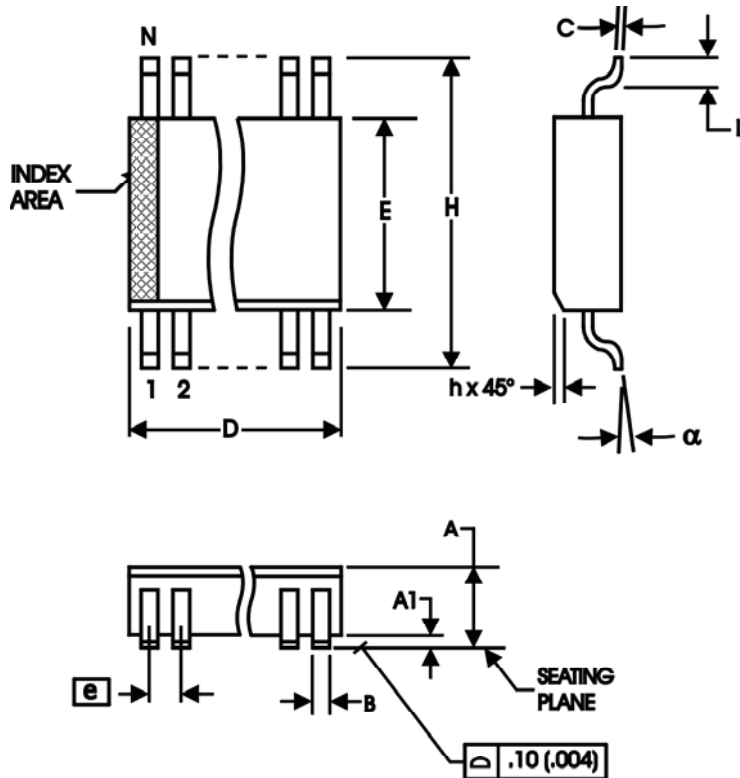
| $\theta_{JA}$ by Velocity (Linear Feet per Minute) |           |           |           |
|--|-----------|-----------|-----------|
|  | 0         | 200       | 500       |
| Single-Layer PCB, JEDEC Standard Test Boards       | 153.3°C/W | 128.5°C/W | 115.5°C/W |
| Multi-Layer PCB, JEDEC Standard Test Boards        | 112.7°C/W | 103.3°C/W | 97.1°C/W  |

**NOTE:** Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

**TRANSISTOR COUNT**

The transistor count for 8304I is: 416

## PACKAGE OUTLINE AND DIMENSIONS

**PACKAGE OUTLINE - SUFFIX M FOR 8 LEAD SOIC**

**TABLE 6. PACKAGE DIMENSIONS - SUFFIX M**

| SYMBOL | Millimeters |         |
|--------|-------------|---------|
|        | MINIMUM     | MAXIMUM |
| N      | 8           |         |
| A      | 1.35        | 1.75    |
| A1     | 0.10        | 0.25    |
| B      | 0.33        | 0.51    |
| C      | 0.19        | 0.25    |
| D      | 4.80        | 5.00    |
| E      | 3.80        | 4.00    |
| e      | 1.27 BASIC  |         |
| H      | 5.80        | 6.20    |
| h      | 0.25        | 0.50    |
| L      | 0.40        | 1.27    |
| alpha  | 0°          | 8°      |

Reference Document: JEDEC Publication 95, MS-012



**TABLE 7. ORDERING INFORMATION**

| <b>Part/Order Number</b> | <b>Marking</b> | <b>Package</b>          | <b>Shipping Packaging</b> | <b>Temperature</b> |
|--------------------------|----------------|-------------------------|---------------------------|--------------------|
| 8304AMILF                | 8304AMIL       | 8 lead "Lead Free" SOIC | Tube                      | -40°C to +85°C     |
| 8304AMILFT               | 8304AMIL       | 8 lead "Lead Free" SOIC | Tape and Reel             | -40°C to +85°C     |

| REVISION HISTORY SHEET |           |             |  |          |
|------------------------|-----------|-------------|--|----------|
| Rev                    | Table     | Page        | Description of Change  | Date     |
| B                      | 3B        | 3           | LVC MOS/LVTTL DC Characteristics Table, added $I_{OH}$ and $I_{OL}$ Test Conditions to $V_{OH}$ and $V_{OL}$ rows.   | 4/4/02   |
| B                      | T7        | 1<br>8      | Features Section - added lead-free bullet.<br>Ordering Information Table - added lead-free part number, marking and note.<br>Updated datasheet format.   | 11/09/06 |
| C                      | T4A<br>T7 | 4<br>6<br>9 | 3.3V AC Characteristics Table - added Buffer Additive Phase Jitter spec.<br>Added Buffer Additive Phase Jitter Plot.<br>Ordering Information - Deleted "ICS" from the Part/Order number column.                                      | 2/11/09  |
| D                      | T1<br>T2  | 1<br>2<br>2 | Pin Assignment - corrected "pullup" label to "pulldown" label.<br>Pin Description Table - deleted pullup from note.<br>Pin Characteristics Table - deleted Rpullup row.  | 10/29/10 |
| D                      | T7        | 9           | Removed ICS in the part numbers.<br>Removed LF note at the bottom of the Ordering Information table.<br>Removed the quantity of 2500 from the Tape & Reel in the Ordering information table.<br>Updated datasheet header and footer. | 12/10/15 |



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